

Notice of References Cited

Application/Control No. 10/674,292	Applicant(s)/Patent Under Reexamination HASEI ET AL.
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Examiner Yewebdar T Tadesse	Art Unit 1734	Page 1 of 1
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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2003/0137242	07-2003	Seki, Shunichi	313/506
B	US-2003/0008217	01-2003	Kobayashi, Hironori	430/5
C	US-2003/0059686	03-2003	Kobayashi et al.	430/5
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FOREIGN PATENT DOCUMENTS

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